

=

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600 V

25 mΩ

100 A

105

Normally – OFF Silicon Carbide Junction Transistor

Features

- 210°C maximum operating temperature
- Gate Oxide Free SiC Switch
- Exceptional Safe Operating Area
- Excellent Gain Linearity
- Compatible with 5 V TTL Gate Drive
- Temperature Independent Switching Performance
- Low Output Capacitance
- Positive Temperature Coefficient of R_{DS,ON}
- Suitable for Connecting an Anti-parallel Diode

Advantages

- Compatible with Si MOSFET/IGBT Gate Drive ICs
- > 20 µs Short-Circuit Withstand Capability
- Lowest-in-class Conduction Losses
- High Circuit Efficiency
- Minimal Input Signal Distortion
- High Amplifier Bandwidth

Package



 V_{DS}

R_{DS(ON)}

 I_D (Tc = 25°C)

h_{FE (Tc = 25°C)}

Applications

- Down Hole Oil Drilling
- Geothermal Instrumentation
- Solenoid Actuators
- General Purpose High-Temperature Switching
- Amplifiers
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)

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Section I: Absolute Maximum Ratings

Parameter	Symbol	Conditions	Value	Unit	Notes
Drain – Source Voltage	V _{DS}	$V_{GS} = 0 V$	600	V	
Continuous Drain Current	Ι _D	T _J = 210°C, T _C = 25°C	100	А	
Continuous Gate Current	I _{GM}		3.5	А	
Turn-Off Safe Operating Area	RBSOA	T_J = 210°C, I _G = 3.5 A, Clamped Inductive Load	$I_{D,max} = 50$ @ $V_{DS} \le V_{DSmax}$	А	Fig. 18
Short Circuit Safe Operating Area	SCSOA	T_J = 210°C, I_G = 3.5 A, V_{DS} = 400 V, Non Repetitive	>20	μs	
Reverse Gate – Source Voltage	V _{SG}		30	V	
Reverse Drain – Source Voltage	V _{SD}		25	V	
Power Dissipation	P _{tot}	T _J = 210°C, T _C = 25°C	769	W	Fig. 16
Operating and Storage Temperature	T _{stg}		-55 to 210	°C	

Section II: Static Electrical Characteristics

Baramatar	Symbol	Conditions	Value		11	N	
Parameter Syn		ool Conditions		Min. Typical Max.		Unit	Notes
A: On State							
Drain – Source On Resistance	R _{DS(ON)}	$\begin{array}{l} I_{D} = 50 \text{ A}, \ T_{j} = 25 \ ^{\circ}\text{C} \\ I_{D} = 50 \text{ A}, \ T_{j} = 125 \ ^{\circ}\text{C} \\ I_{D} = 50 \text{ A}, \ T_{j} = 175 \ ^{\circ}\text{C} \end{array}$		25 39 43		mΩ	Fig. 5
		I _D = 50 A, T _j = 210 °C		50			
Gate – Source Saturation Voltage	$V_{\text{GS,SAT}}$	$I_D = 50 \text{ A}, I_D/I_G = 40, T_j = 25 \text{ °C}$ $I_D = 50 \text{ A}, I_D/I_G = 30, T_j = 175 \text{ °C}$		3.42 3.23		V	Fig. 7
DC Current Gain	h _{FE}	$ \begin{array}{l} V_{DS}=5 \; V, \; I_{D}=50 \; A, \; T_{j}=25 \; ^{\circ} C \\ V_{DS}=5 \; V, \; I_{D}=50 \; A, \; T_{j}=125 \; ^{\circ} C \\ V_{DS}=5 \; V, \; I_{D}=50 \; A, \; T_{j}=175 \; ^{\circ} C \\ V_{DS}=5 \; V, \; I_{D}=50 \; A, \; T_{j}=210 \; ^{\circ} C \end{array} $		105 77 71 70		_	Fig. 5
B: Off State							
Drain Leakage Current	I _{DSS}	$ \begin{array}{l} V_{\rm R} = 600 \; V, V_{\rm GS} = 0 \; V, T_{\rm J} = 25 \; ^{\circ}{\rm C} \\ V_{\rm R} = 600 \; V, V_{\rm GS} = 0 \; V, T_{\rm J} = 125 \; ^{\circ}{\rm C} \\ V_{\rm R} = 600 \; V, V_{\rm GS} = 0 \; V, T_{\rm J} = 210 \; ^{\circ}{\rm C} \end{array} $		10 50 100		μA	Fig. 8
Gate Leakage Current	I _{SG}	V _{SG} = 20 V, T _j = 25 °C		20		nA	
C: Thermal							
Thermal resistance, junction - case	R _{thJC}			0.26		°C/W	Fig. 1

Section III: Dynamic Electrical Characteristics

Baramatar	Symphol	Conditions		Value		Unit	Notes
Parameter	Symbol	Conditions	Min.	Typical	Max.	Unit	Notes
A: Capacitance and Gate Charg	e						
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _D = 100 V, <i>f</i> = 1 MHz		6450		pF	Fig. 9
Reverse Transfer/Output Capacitance	C _{rss} /C _{oss}	V _D = 100 V, <i>f</i> = 1 MHz		420		pF	Fig. 9
Output Capacitance Stored Energy	Eoss	V _{GS} = 0 V, V _D = 400 V, <i>f</i> = 1 MHz		17.4		μJ	Fig. 10
Effective Output Capacitance, time related	C _{oss,tr}	I_{D} = constant, V_{GS} = 0 V, V_{DS} = 0400 V		390		pF	
Effective Output Capacitance, energy related	$C_{\text{oss,er}}$	V_{GS} = 0 V, V_{DS} = 0400 V		284		pF	
Gate-Source Charge	Q _{GS}	V _{GS} = -53 V		55		nC	
Gate-Drain Charge	Q_{GD}	V _{GS} = 0 V, V _{DS} = 0400 V		156		nC	
Gate Charge - Total	Q_{G}			211		nC	
B: Switching ¹							
Internal Gate Resistance – zero bias	R _{G(INT-ZERO)}	<i>f</i> = 1 MHz, V _{AC} = 50 mV, V _{DS} = 0 V, V _{GS} = 0 V, T _i = 210 °C		0.9		Ω	
Internal Gate Resistance – ON	R _{G(INT-ON)}	V _{GS} > 2.5 V, V _{DS} = 0 V, T _j = 210 °C		0.09		Ω	
Turn On Delay Time	t _{d(on)}	T _i = 25 °C, V _{DS} = 400 V,		25		ns	
Fall Time, V _{DS}	t _f	$I_{\rm D} = 50$ A, Resistive Load		44		ns	Fig. 11,13
Turn Off Delay Time	t _{d(off)}	Refer to Section V for additional		40		ns	
Rise Time, V _{DS}	tr	driving information.		33		ns	Fig. 12,14
Turn On Delay Time	t _{d(on)}			19		ns	
Fall Time, V _{DS}	t _f	T _i = 210 °C, V _{DS} = 400 V,		43		ns	Fig. 11
Turn Off Delay Time	t _{d(off)}	$I_{\rm D}$ = 50 A, Resistive Load		89		ns	
		_					

Turn-On Energy Per Pulse Turn-Off Energy Per Pulse Total Switching Energy

Turn-Off Energy Per Pulse Total Switching Energy $\mathsf{E}_{\mathsf{tot}}$ 1 – All times are relative to the Drain-Source Voltage V_{DS}

tr E_{on}

 $\mathsf{E}_{\mathsf{off}}$

E_{tot}

Eon

E_{off}

Rise Time, V_{DS}

Turn-On Energy Per Pulse

 $T_j = 25 \text{ °C}, V_{DS} = 400 \text{ V},$ $I_D = 50 \text{ A}, \text{ Inductive Load}$ Refer to Section V.

T_i = 210 °C, V_{DS} = 400 V,

 $-I_D = 50 \text{ A}$, Inductive Load

Fig. 12

Fig. 11,13

Fig. 12,14

Fig. 11

Fig. 12

ns

μJ

μJ

μJ

μJ

μJ

μJ

27

690

359

1049

758

337

1095

GA50JT06-258

Section IV: Figures A: Static Characteristics







Figure 5: Normalized On-Resistance and Current Gain vs. Temperature









Figure 8: Typical Blocking Characteristics





B: Dynamic Characteristics

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Figure 9: Input, Output, and Reverse Transfer Capacitance









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Figure 13: Typical Turn On Energy Losses and Switching Times vs. Drain Current



Figure 15: Typical Hard Switched Device Power Loss vs. Switching Frequency²





Figure 14: Typical Turn Off Energy Losses and Switching Times vs. Drain Current



Figure 16: Power Derating Curve



² – Representative values based on device conduction and switching loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.

GeneSiC SEMICONDUCTOR

GA50JT06-258



Figure 19: Transient Thermal Impedance



Figure 20: Drain Current Derating vs. Pulse Width



Section V: Driving the GA50JT06-247

The GA50JT06-247 is a current controlled SiC transistor which requires a positive gate current for turn-on and to remain in on-state. It may be driven by different drive topologies depending on the intended application.

Drive Topology	Gate Drive Power Consumption	Switching Frequency
Simple TTL	High	Low
Constant Current	Medium	Medium
High Speed – Boost Capacitor	Medium	High
High Speed – Boost Inductor	Low	High
Proportional	Lowest	Medium
Pulsed Power	Medium	N/A

Table 1: Estimated Power Consumption and switchin	g frequencies for various Gate Drive topologies.
---	--

A: Simple TTL Drive

The GA50JT06-247 may be driven by 5 V TTL logic by using a simple current amplification stage. The current amplifier output current must meet or exceed the steady state gate current, $I_{G,steady}$, required to operate the GA50JT06-247. An external gate resistor R_G , shown in the Figure 21 topology, sets $I_{G,steady}$ to the required level which is dependent on the SJT drain current I_D and DC current gain h_{FE} , R_G may be calculated from the equation below. The values of h_{FE} and $V_{GS,sat}$ may be read from Figure 6 and Figure 7, respectively. $V_{EC,sat}$ can be taken from the PNP datasheet, a partial list of high-temperature PNP and NPN transistors options is given below. High-temperature MOSFETs may also be used in the topology.

$$R_{G,max} = \frac{(5.0 V - V_{EC,sat}(PNP) - V_{GS,sat}(SJT)) * h_{FE}(T, I_D)}{I_D * 1.5}$$



Figure 21: Simple TTL Gate Drive Topology

Table 2: Partial List of High-Temperature BJTs for TTL Gate Driving						

BJT Part Number	Туре	T _{j,max} (°C)
PHPT60603PY	PNP	175
PHPT60603NY	NPN	175
2N2222	NPN	200
2N6730	PNP	200
2N2905	PNP	200
2N5883	PNP	200
2N5885	NPN	200

B: High Speed Driving

For ultra high speed GA50JT06-247 switching (t_r , t_r < 20 ns) while maintaining low gate drive losses the supplied gate current should include a positive current peak during turn-on, a negative voltage peak during turn-off, and continuous gate current I_G to remain on.

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge for turn-on, Q_G , is supplied by a burst of high gate current until the gate-source capacitance, C_{GS} , and gate-drain capacitance, C_{GD} , are fully charged. Ideally, the burst should terminate when the drain voltage has fallen to its on-state value in order to avoid unnecessary drive losses. A negative voltage peak is recommended for the turn-off transition in order to ensure that the gate current is not being supplied under high dV/dt due to the Miller effect. While satisfactory turn off can be achieved with $V_{GS} = 0 V$, a negative V_{GS} value may be used in order to speed up the turn-off transition.

B:1: High Speed, Low Loss Drive with Boost Capacitor

The GA50JT06-247 may be driven using a High Speed, Low Loss Drive with Boost Capacitor topology in which multiple voltage levels, a gate resistor, and a gate capacitor are used to provide current peaks at turn-on and turn-off for fast switching and a continuous gate current while in on-state. As shown in Figure 22, in this topology two gate driver ICs are utilized. An external gate resistor R_G is driven by a low voltage driver to supply the continuous gate current throughout on-state. and a gate capacitor C_G is driven at a higher voltage level to supply a high current peak at turn-on and turn-off. A 3 kV isolated evaluation gate drive board (GA03IDDJT30-FR4) from GeneSiC Semiconductor utilizing this topology is commercially available for high and low-side driving, its datasheet provides additional details about this drive topology.



Figure 22: High Speed, Low Loss Drive with Boost Capacitor Topology

B:2: High Speed, Low Loss Drive with Boost Inductor

A High Speed, Low-Loss Driver with Boost Inductor is also capable of driving the GA50JT06-247 at high-speed. It utilizes a gate drive inductor instead of a capacitor to provide the high-current gate current pulses $I_{G,on}$ and $I_{G,off}$. During operation, inductor L is charged to a specified $I_{G,on}$ current value then made to discharge I_L into the SJT gate pin using logic control of S_1 , S_2 , S_3 , and S_4 , as shown in Figure 23. After turn on, while the device remains on the necessary steady state gate current $I_{G,steady}$ is supplied from source V_{CC} through R_G . Please refer to the article "A current-source concept for fast and efficient driving of silicon carbide transistors" by Dr. Jacek Rąbkowski for additional information on this driving topology.³



Figure 23: High Speed, Low-Loss Driver with Boost Inductor Topology

³ – Archives of Electrical Engineering. Volume 62, Issue 2, Pages 333–343, ISSN (Print) 0004-0746, DOI: 10.2478/aee-2013-0026, June 2013



C: Proportional Gate Current Driving

A proportional gate drive topology may be beneficial for applications in which the GA50JT06-247 will operate over a wide range of drain current conditions to lower the gate drive power consumption. A proportional gate driver relies on instantaneous drain current I_D feedback to vary the steady state gate current $I_{G,steady}$ supplied to the GA50JT06-247.

C:1: Voltage Controlled Proportional Driver

A voltage controlled proportional driver relies on a gate drive integrated circuit to detect the GA50JT06-247 drain-source voltage V_{DS} during on-state to sense I_D . The integrated circuit will then increase or decrease I_G in response to I_D . This allows I_G and gate drive power consumption to reduce while I_D is low or for I_G to increase when I_D increases. A high voltage diode connected between the drain and sense protects the integrated circuit from high-voltage when blocking. A simplified version of this topology is shown in Figure 24. Additional information will be available in the future at http://www.genesicsemi.com/references/product-notes/.



Figure 24: Simplified Voltage Controlled Proportional Driver

C:2: Current Controlled Proportional Driver

The current controlled proportional driver relies on a low-loss transformer in the drain or source path to provide feedback of the GA50JT06-247 drain current during on-state to supply $I_{G,steady}$ into the gate. $I_{G,steady}$ will increase or decrease in response to I_D at a fixed forced current gain which is set be the turns ratio of the transformer, $h_{force} = I_D / I_G = N_2 / N_1$. GA50JT06-247 is initially tuned-on using a gate current pulse supplied into an RC drive circuit to allow I_D current to begin flowing. This topology allows $I_{G,steady}$ and the gate drive power consumption to reduce while I_D is relatively low or for $I_{G,steady}$ to increase when I_D increases. A simplified version of this topology is shown in Figure 25. Additional information will be available in the future at http://www.genesicsemi.com/references/product-notes/.



Figure 25: Simplified Current Controlled Proportional Driver



Section VI: Package Dimensions



NOTE

1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.

2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History					
Date	Revision	Comments	Supersedes		
2014/12/12	5	Updated Electrical Characteristics			
2014/08/23	4	Updated Electrical Characteristics			
2014/04/10	3	Updated Electrical Characteristics			
2014/02/05	2	Updated Electrical Characteristics			
2013/12/19	1	Updated Gate Drive Section			
2013/12/05	0	Initial release			

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Section VII: SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/hit_sic/sjt/GA50JT06-258_SPICE.pdf) into LTSPICE (version 4) software for simulation of the GA50JT06-258.

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MODEL OF GeneSiC Semiconductor Inc.
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     $Revision: 1.3
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     $Date: 12-DEC-2014
                                   $
*
     GeneSiC Semiconductor Inc.
*
     43670 Trade Center Place Ste. 155
     Dulles, VA 20166
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* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
.model GA50JT06 NPN
+ IS
           5.00E-47
+ ISE
          1.26E-26
+ EG
           3.23
          106
+ BF
+ BR
          0.55
          9000
+ IKF
           1
+ NF
          2
+ NE
          0.9
+ RB
+ IRB
          0.002
+ RBM
          0.09
          0.01
+ RE
          0.013
+ RC
+ CJC
           2.3989E-9
           2.8346223
+ VJC
+ MJC
          0.4846
+ CJE
          6.026E-09
          3.17915435
+ VJE
+ MJE
          0.52951635
+ XTI
          3
+ XTB
          -1.2
+ TRC1
                  7.00E-3
                 600
+ VCEO
+ ICRATING 100
+ MFG GeneSiC Semiconductor
* End of GA50JT06 SPICE Model
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